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Electronic Patent Application Submission

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EFS ID:	55538
Application ID:	10679617
Title of Invention:	METHODS AND SYSTEMS FOR RETICLE INSPECTION AND DEFECT REVIEW USING AERIAL IMAGING
First Named Inventor:	Stan Stokowski
Domestic/Foreign Application:	Domestic Application
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Confirmation number:	3334
Attorney Docket Number:	5589-04101
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Title of Invention	METHODS AND SYSTEMS FOR RETICLE INSPECTION AND DEFECT REVIEW USING AERIAL IMAGING

Application Number: 10/679617
Date: 2003-10-06
First Named Applicant: Stan Stokowski

Confirmation Number: 3334
Attorney Docket Number: 5589-04101

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Submitted by:	Elec. Sign.	Sign. Capacity
Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney

Documents being submitted	Files
us-ids	5589-04001IDS2-usidst.xml us-ids.dtd us-ids.xsl

Comments

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Electronic Version v18
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First Named Applicant: Stan Stokowski
Attorney Docket Number: 5589-04101
Search string: (6636301 or 6614520 or 6529621).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	6636301	2003-10-21	Kvamme et al.			
	2	6614520	2003-09-02	Bareket et al.			
	3	6529621	2003-03-04	Glasser et al.			

Signature

Examiner Name	Date